

The Institute of Electronics of TU Graz is glad to invite
to the closing event of the lecture
„Production Test and Design for Test”



In the context of the lecture „Production Test and Design for Test“ representatives of leading equipment manufacturers could be won as presenters for the closing event.

This event will be held as online conference via Webex on June 30 from 08:30 to 12:00.

Login Info: <https://tugraz.webex.com/tugraz/j.php?MTID=m833f12099ab56afbb17008922fac40f6>

8:30	08:40	Welcome and Greeting Address: Prof. Bernd Deutschmann, Armin Lammer	
08:40	09:20	Accretech: Thomas Printschler, Peter Neundorfer Fully Automated Wafer Probing	www.accretech.de
09:20	10:00	Advantest: Matthias Werner, Hans Giessibl Precision Static ADC Test Using Cost Optimized Sinusoidal Methodology on Advantest V93000	www.advantest.com
10:00	10:40	Cohu: Alexander Waldauf, Markus Wagner Cohu Testing in the Highest Sense <ul style="list-style-type: none"> • New MEMS testing platform Sense+ • New batch contacting 	www.cohu.com
10:40	11:20	FormFactor: Gabriele Vittori Automated Sub Pico & PIV Test on 300mm Wafer at High Temperature	www.formfactor.com
11:20	12:00	Teradyne: Wilhelm Fencel, Vasile Sisu High Volume Testing Challenges in the 5G mmWave Era	www.teradyne.com

In case of questions: phone :+43 677 62867406 e-mail: armin.lammer@tugraz.at